Notice of Ref rences Cited Application/Control No. 10/614,058 Examiner Hoai V Pham Applicant(s)/Patent Under Reexamination INOUE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,570,237	05-2003	Kitamura, Akio	257/499
	В	US-			
	С	US-		·	
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ŀ	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	V					
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	Х					

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